Supertex inc.



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV _{DSS} /	R _{DS(ON)}	V _{GS(th)}	Order Numb	Order Number / Package		
BV _{DGS}	(max)	(max)	TO-243AA**	TO-236AB*		
240V	15Ω	2.0V	TN2124N8	TN2124K1		

Product marking for SOT-23:

N1C*

where * = 2-week alpha date code

Features

	Free from secondary breakdown
	Low power drive requirement
	Ease of paralleling
	Low $C_{\rm ISS}$ and fast switching speeds
	Excellent thermal stability
	Integral Source-Drain diode
	High input impedance and high gain
П	Complementary N- and P-channel devices

Applications

_	ppiications
	Logic level interfaces – ideal for TTL and CMOS
	Solid state relays
	Battery operated systems
	Photo voltaic drives
	Analog switches
	General purpose line drivers
П	Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV _{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

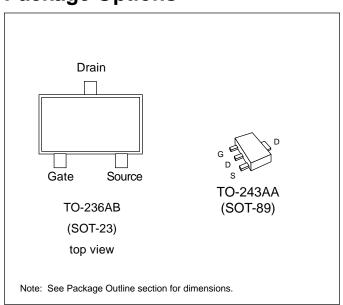
^{*} Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options



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^{*} Same as SOT-23. All units shipped on 3,000 piece carrier tape reels.

^{**} Prodcut supplied on 2000 piece carrier tape reels.

Thermal Characteristics

Package	I _D (continuous)*	I _D (pulsed)	Power Dissipation @ T _A = 25°C	$^{ heta_{ m jc}}$ $^{\circ}$ C/W	$ heta_{\sf ja}$ $^{\circ}$ C/W	I _{DR} *	I _{DRM}
TO-236AB	134mA	250mA	0.36W	200	350	134mA	250mA
TO-243AA	230mA	1.1A	1.6W [†]	15	78 [†]	230mA	1.1A

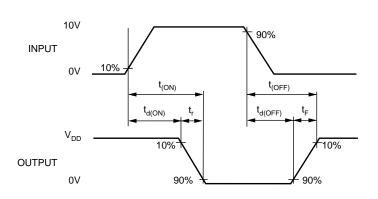
^{*} I_D (continuous) is limited by max rated T_j .

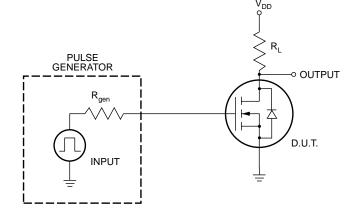
Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter	Min	Тур	Max	Unit	Conditions	
BV _{DSS}	Drain-to-Source Breakdown Voltage	240			V	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}$	
V _{GS(th)}	Gate Threshold Voltage	0.8		2.0	V	$V_{GS} = V_{DS}$, $I_D = 1mA$	
$\Delta V_{GS(th)}$	Change in V _{GS(th)} with Temperature			-5.5	mV/°C	$I_D = 1 \text{mA}, V_{GS} = V_{DS}$	
I _{GSS}	Gate Body Leakage		0.1	100	nA	$V_{GS} = \pm 20V$, $V_{DS} = 0V$	
I _{DSS}	Zero Gate Voltage Drain Current			1	μΑ	$V_{GS} = 0V$, $V_{DS} = Max$ Rating	
				100	μА	$V_{GS} = 0V$, $V_{DS} = 0.8$ Max Rating $T_A = 125$ °C	
I _{D(ON)}	ON-State Drain Current	140			mA	$V_{GS} = 4.5V, V_{DS} = 25V$	
R _{DS(ON)}	Static Drain-to-Source ON-State Resistance			30	Ω	$V_{GS} = 3V$, $I_D = 25mA$	
				15	Ω	$V_{GS} = 4.5V, I_D = 120mA$	
$\Delta R_{DS(ON)}$	Change in R _{DS(ON)} with Temperature		0.7	1.0	%/°C	$I_D = 120 \text{mA}, V_{GS} = 4.5 \text{V}$	
G _{FS}	Forward Transconductance	100	170		mΩ	$V_{DS} = 25V, I_{D} = 120mA$	
C _{ISS}	Input Capacitance		38	50			
C _{oss}	Common Source Output Capacitance		9	15	pF	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	
C_{RSS}	Reverse Transfer Capacitance		3	5			
$t_{d(ON)}$	Turn-ON Delay Time		4	7		$V_{DD} = 25V$ $I_{D} = 140 \text{mA}$ $R_{GEN} = 25\Omega$	
t _r	Rise Time		2	5	ns		
$t_{d(OFF)}$	Turn-OFF Delay Time		7	10	. 113		
t _f	Fall Time		9	12		OLIV	
V _{SD}	Diode Forward Voltage Drop			1.8	V	$I_{SD} = 120 \text{mA}, V_{GS} = 0 \text{V}$	
t _{rr}	Reverse Recovery Time		400		ns	$I_{SD} = 120 \text{mA}, V_{GS} = 0 \text{V}$	

Notes:

Switching Waveforms and Test Circuit



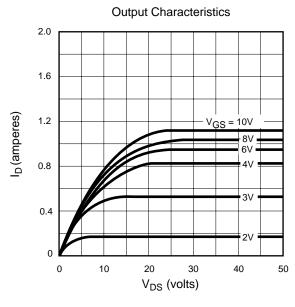


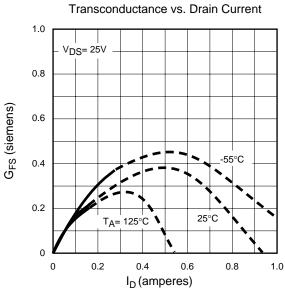
 $^{^\}dagger$ Mounted on FR5 board. 25mmx25mmx1.57mm. Significant P_D increase possible on ceramic substrate.

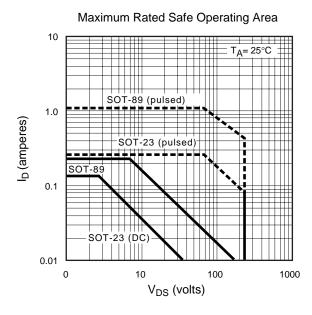
 $^{1.} All\ D.C.\ parameters\ 100\%\ tested\ at\ 25^{\circ}C\ unless\ otherwise\ stated.\ (Pulse\ test:\ 300\mu s\ pulse,\ 2\%\ duty\ cycle.)$

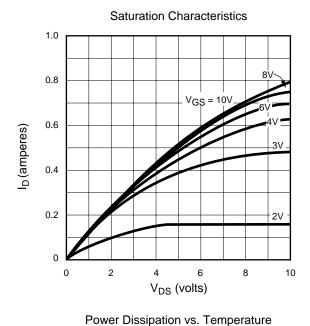
^{2.}All A.C. parameters sample tested.

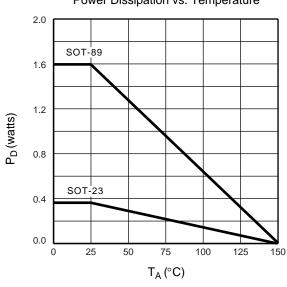
Typical Performance Curves

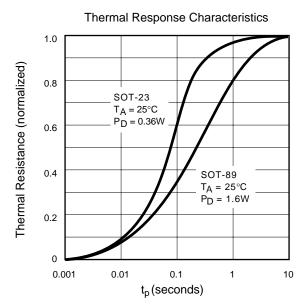












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Typical Performance Curves

